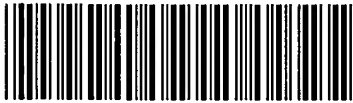


Search Notes

Application/Control No.

10/628,327

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

IIDA, TAKAYUKI

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	207.2	4/12/2007	NT
348	211.2	4/12/2007	NT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	4/12/2007	NT
text search all databases listed above -- see search history printout	4/12/2007	NT